REV	COUNT	DESCRIPTION OF REVISIONS	BY	CHKD	DATE	REV	COUNT	DESCRIPTION OF REVISIONS	BY	CHKD	DATE
2	–	REVISED	JS.PARK	HJ.LEE	16.08.03	4	–	REVISED	JS.PARK	HJ.KIM	16.12.07
3	–	REVISED	JS.PARK	HJ.LEE	16.10.12	5	2	REVISED	HJ.KIM	HJ.LEE	17.10.13

APPLICABLE STANDARD		USB Type-C Cable and Connector Specification Release 1.2 USB Type-C Connector and Cable Assemblies Compliance Document Revision 1.0
RATING	5 CURRENT	DC 1.25A max. for each power pin (i.e. A1, A4, A9, A12, B1, B4, B5, B9, B12) DC 0.25A for the other pins
	VOLTAGE	20VAC
OPERATING CONDITION		-30℃ ~ +85℃(INCLUDING TEMP. RISE), 95% RH MAX.(NON-CONDENSING)
STORAGE CONDITION		-10℃ ~ +60℃(WITH PACKING), 15% ~ 70% RH

Para.	Test Description	Test Procedure	Test Requirement	QT	AT
1	Examination of product	EIA 364-18 Visual inspection	No physical damage	O	O
Electrical Requirements					
2	Low Level Contact Resistance	EIA 364-23 Measure at 20mV max open circuit at 100mA(DC OR 1000Hz). 4-wire measurement is required and the resistance of PCB termination shall be deducted from the reading.	40mΩ max initial for each contact. 50mΩ max after initial measurement.	O	–
3	Dielectric Withstanding Voltage	EIA 364-20 Measure per Method B with unmated condition. 100VAC RMS for 1 minute at sea level.	No distruptive discharge.	O	–
4	Insulation Resistance	EIA 364-21 500VDC with unmated and mated condition.	100MΩ Min.	O	–
Mechanical Requirements					
5	Insertion force	EIA 364-13 Measure at 12.5mm/minute min.	5N to 20N	O	–
6	Extraction force	EIA 364-13 Measure at 12.5mm/minute min.	Initial : 8N to 20N After test : 6N to 20N	O	–
7	Durability	EIA 364-09 10,000 insertion/extration cycles Cycle rate : 500±50 cycles per hour.	Low level contact resistance and dielectric withstanding voltage shall meet the spec after test.	O	–
8	Vibration	EIA 364-28 Test Condition VII, Test Letter D 20-500 Hz random levels, 15minutes in each of 3 mutually perpendicular directions.	No physical damage and no discontinuity longer than 1us. Low level contact resistance meets spec before and after the test.	O	–

REMARKS	DRAFT	DESIGN	CHECK	APPROVAL	RELEASE
HIROSE will not guarantee the performance on these specifications in case this product will be mated with the others which is not HIROSE's 5	JS.PARK 16.08.03	JS.PARK 16.08.03	HJ.LEE 16.08.03	TS.KANG 16.08.03	DEPT 17.10.13 ENG

NOTE) QT : QUALIFICATION TEST, AT : ASSURANCE TEST, O: Applicable Test

DWG NO	CL NO	PART NO
ELC4-631979	CL 6240-0001-9	CX60-24S-UNIT

HIROSE KOREA.CO.,LTD	PRODUCT SPECIFICATION	1 / 3

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Para.	Test Description	Test Procedure	Test Requirement	QT	AT
Environmental Requirements					
9	Temperature Life	EIA 364-17, Method A 105℃ without applied voltage for 120hours.	Low level contact resistance meets spec before and after the test.	O	-
10	Cyclic Temperature and Humidity	EIA 364-31 25±3°C at 80±3% RH for 1 hour. 65±3°C at 50±3% RH for 1 hour. Thermal ramp : 0.5 hour Number of cycles : 24 cycles	Low level contact resistance meets spec before and after the test.	O	-
11	Thermal Shock	EIA 364-32, Test Condition I 10cycles -55°C and +85°C	No physical damage. Low level contact resistance meets spec before and after the test.	O	-
12	Damp Heat (Steady State)	+85℃ and 85%RH for 120hours in mated condition.	No physical damage. Low level contact resistance meets spec before and after the test.	O	-
13	Solderability	EIA 364-52 Dwell in 245℃±5℃ of the solder bath for 5sec.	Solder coverage shall be 95% min.of the immersed surfaces.	O	-
14	Salt Spray	EIA 364-26 5% of NaCl in 35℃ for 48hours	No corrosions that affect to connector operation. Low level contact resistance meets spec before and after the test.	O	-

REMARKS

NOTE) QT : QUALIFICATION TEST, AT : ASSURANCE TEST, O: Applicable Test

DWG NO	CL NO	PART NO
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Qualification Test Sequence Table

Para.	Test Description	Test Group							
		A	B	C	D	E	F	G	H
1	Examination of product	O	O	O	O	O	O	O	O
2	Low Level Contact Resistance	O	O	O	O	O	O		O
3	Dielectric Withstanding Voltage		O						
4	Insulation Resistance		O						
5	Insertion force		O						
6	Extraction force		O						
7	Durability		O						
8	Vibration	O							
9	Temperature Life			O					
10	Cyclic Temperature and Humidity				O				
11	Thermal Shock					O			
12	Damp Heat (Steady State)						O		
13	Solderability							O	
14	Salt Spray								O

REMARKS

1) Numbers in the table above indicate the sequence corresponding to each test group.

NOTE) QT : QUALIFICATION TEST, AT : ASSURANCE TEST, O: Applicable Test

DWG NO	CL NO	PART NO
ELC4-631979	CL 6240-0001-9	CX60-24S-UNIT

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